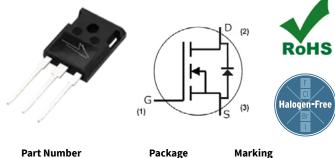


Silicon Carbide Power MOSFET C3M™ MOSFET Technology N-Channel Enhancement Mode

#### **Features**

- 3rd generation SiC MOSFET technology
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Q<sub>rr</sub>)
- Halogen free, RoHS compliant



Part Number	Package	Marking
C3M0040120D	TO 247-3	C3M0040120D

## **Applications**

- Solar inverters
- EV motor drive
- High voltage DC/DC converters
- Switched mode power supplies

#### **Benefits**

- · Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

#### **Key Parameters**

Parameter	Symbol	Min.	Тур.	Max	Unit	Conditions	Note
Drain - Source Voltage	V <sub>DS</sub>			1200	V	T <sub>c</sub> = 25°C	
Maximum Gate - Source Voltage	V <sub>GS(max)</sub>	-8		+19	] V	Transient	
Operational Gate-Source Voltage	V <sub>GS op</sub>		-4/15			Static	Note 1
DC Comtinuous Dunin Courset				66		$V_{GS} = 15 \text{ V}, T_{C} = 25 \text{ °C}, T_{J} \le 175 \text{ °C}$	Fig. 19
DC Continuous Drain Current	l <sub>D</sub>			48	А	$V_{GS} = 15 \text{ V}, T_{C} = 100 \text{ °C}, T_{J} \le 175 \text{ °C}$	Note 2
Pulsed Drain Current	I <sub>DM</sub>			223		t <sub>Pmax</sub> limited by T <sub>jmax</sub> V <sub>GS</sub> = 15V, T <sub>C</sub> = 25 °C	Fig. 22
Power Dissipation	P <sub>D</sub>			326	W	$T_{c} = 25^{\circ}C, T_{J} = 175^{\circ}C$	Fig. 20
Operating Junction and Storage Temperature	T <sub>J</sub> , T <sub>stg</sub>			-40 to +175	°C		
Solder Temperature	T <sub>L</sub>			260		According to JEDEC J-STD-020	
Mounting Torque	M <sub>D</sub>			1 8.8	Nm Ibf-in	M3 or 6-32 screw	

Note (1): Recommended turn-on gate voltage is 15V with ±5% regulation tolerance, see Application Note PRD-04814 for additional details

Note (2): Verified by design

## **Electrical Characteristics** ( $T_c = 25$ °C unless otherwise specified)

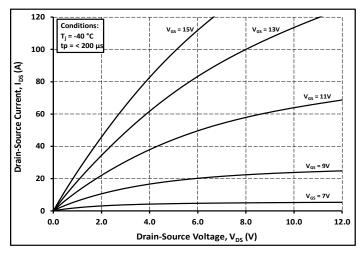
Parameter	Symbol	Min.	Тур.	Max.	Unit	<b>Test Conditions</b>	Note	
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	1200	_	_		$V_{GS} = 0 \text{ V}, I_{D} = 100 \mu\text{A}$		
Cata Thurshald Valtage		1.8	2.7	3.6	V	$V_{DS} = V_{GS}, I_D = 9.2 \text{ mA}$	F: 44	
Gate Threshold Voltage	$V_{GS(th)}$	_	2.2	_		$V_{DS} = V_{GS}, I_{D} = 9.2 \text{ mA}, T_{J} = 175^{\circ}\text{C}$	Fig. 11	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	1	50	μΑ	V <sub>DS</sub> = 1200 V, V <sub>GS</sub> = 0 V		
Gate-Source Leakage Current	I <sub>GSS</sub>	_	10	250	nA	V <sub>GS</sub> = 15 V, V <sub>DS</sub> = 0 V		
Durin Course On State Besisters	Б	_	40	53.5	0	V <sub>GS</sub> = 15 V, I <sub>D</sub> = 33.3 A	Fig. 4, 5, 6	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	_	68	_	mΩ	V <sub>GS</sub> = 15 V, I <sub>D</sub> = 33.3 A, T <sub>J</sub> = 175°C		
			21		_	V <sub>DS</sub> = 20 V, I <sub>DS</sub> = 33.3 A	<u> </u>	
Transconductance	g <sub>fs</sub>	_	20	_	S	$V_{DS} = 20 \text{ V}, I_{DS} = 33.3 \text{ A}, T_{J} = 175^{\circ}\text{C}$	Fig. 7	
Input Capacitance	C <sub>iss</sub>	_	2900	_				
Output Capacitance	C <sub>oss</sub>	_	103	_	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 1000 \text{ V}$	Fig. 17, 18	
Reverse Transfer Capacitance	C <sub>rss</sub>	_	5	_		$f = 100 \text{ khz}$ $V_{AC} = 25 \text{ mV}$		
Output Capacitance Stored Energy	E <sub>oss</sub>	_	60	_	μJ		Fig. 16	
Turn-On Switching Energy (SiC Diode FWD)	Eon	_	950	_				
Turn Off Switching Energy (SiC Diode FWD)	E <sub>off</sub>	_	346	_	$V_{DS} = 800 \text{ V}, V_{GS} = -4 \text{ V}/+15 \text{ V},$ $I_D = 33.3 \text{ A}, R_{G(ext)} = 2.5 \Omega,$ $L = 99 \text{ μH}, T_J = 175 ^{\circ}\text{C}$		Fig. 26	
Turn-On Switching Energy (Body Diode FWD)	E <sub>on</sub>	_	1645	_				
Turn-Off Switching Energy (Body Diode FWD)	E <sub>off</sub>	_	287	_				
Turn-On Delay Time	t <sub>d(on)</sub>	_	15	_		$V_{DD} = 800 \text{ V}, V_{GS} = -4 \text{ V}/+15 \text{ V}$		
Rise Time	t <sub>r</sub>	_	60	_	$I_D = 33.3 \text{ A}, R_{G(ext)} = 2.5 \Omega,$		<b>-</b> : 0-	
Turn-Off Delay Time	$t_{d(off)}$	_	25	_	ns	L= 99 μH Timing relative to V <sub>DS</sub>	Fig. 27	
Fall Time	t <sub>f</sub>	_	12	_		Inductive load		
Internal Gate Resistance	R <sub>G(int)</sub>	_	3.5	_	Ω	$f = 1 \text{ MHz}, V_{AC} = 25 \text{ mV}$		
Gate to Source Charge	Q <sub>gs</sub>		32	_		V <sub>DS</sub> = 800 V, V <sub>GS</sub> = -4 V/15 V		
Gate to Drain Charge	$Q_{\mathrm{gd}}$	_	29	_	nC	I <sub>D</sub> = 33.3 A	Fig. 12	
Total Gate Charge	$Q_{\rm g}$		101		Per IEC60747-8-4 pg 21			

## **Reverse Diode Characteristics** ( $T_c = 25^{\circ}$ C unless otherwise specified)

Parameter	Symbol	Тур.	Max.	Unit	<b>Test Conditions</b>	Notes
B: 1 5 1V II	.,	5.5	_	V	$V_{GS} = -4 \text{ V}, I_{SD} = 20 \text{ A}, T_{J} = 25^{\circ}\text{C}$	Fig. 8, 9, 10
Diode Forward Voltage	$V_{SD}$	4.9	_		$V_{GS} = -4 \text{ V}, I_{SD} = 20 \text{ A}, T_{J} = 175^{\circ}\text{C}$	
Continuous Diode Forward Current	Is	_	51		V <sub>GS</sub> = -4 V, T <sub>J</sub> = 25°C	Note 1
Diode Pulse Current	I <sub>S, pulse</sub>	_	223	A	$V_{GS} = -4 V$ , pulse width $t_P$ limited by $T_{j max}$	Note 1
Reverse Recovery Time <sup>1</sup>	t <sub>rr</sub>	45	_			
Reverse Recovery Charge <sup>1</sup>	Qrr	697	_	ns	$V_{GS} = -4 \text{ V}, I_{SD} = 33.3 \text{ A}, V_{R} = 800 \text{ V}$ $di_{c}/dt = 1150 \text{ A}/\mu\text{s}, T_{J} = 175^{\circ}\text{C}$	Note 1
Peak Reverse Recovery Current <sup>1</sup>	I <sub>rrm</sub>	26	_		,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	
Reverse Recovery Time,	t <sub>rr</sub>	53	_	nC		
Reverse Recovery Charge	Qrr	624	_		$V_{GS} = -4 \text{ V}, I_{SD} = 33.3 \text{ A}, V_{R} = 800 \text{ V}$ $di_{z}/dt = 800 \text{ A}/\mu\text{s}, T_{J} = 175^{\circ}\text{C}$	
Peak Reverse Recovery Current	I <sub>rrm</sub>	17	_	A		

## **Thermal Characteristics**

Parameter	Symbol	Тур	Unit	Note
Thermal Resistance from Junction to Case	$R_{ heta$ JC	0.46	9C /M	Fig. 21
Thermal Resistance From Junction to Ambient	$R_{\theta JA}$	40	°C/W	Fig. 21



**Figure 1.** Output Characteristics  $T_J = -40^{\circ}C$ 

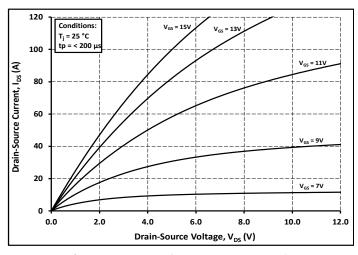


Figure 2. Output Characteristics T<sub>J</sub> = 25°C

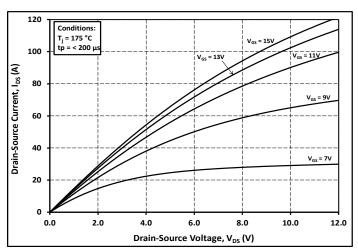


Figure 3. Output Characteristics T<sub>J</sub> = 175°C

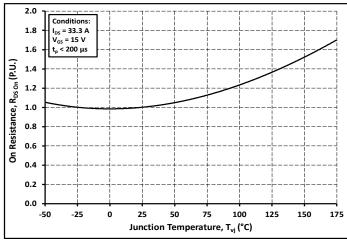
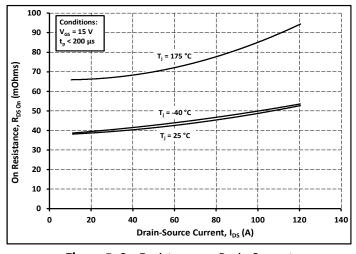
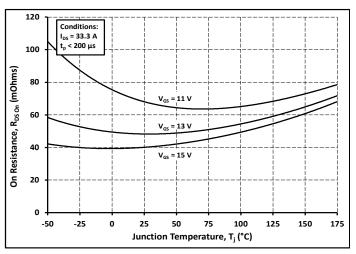


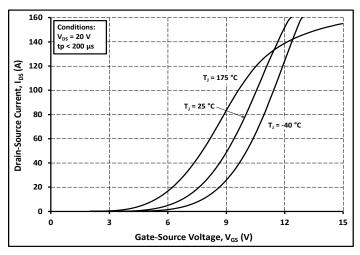
Figure 4. Normalized On-Resistance vs. Temperature



**Figure 5.** On-Resistance vs. Drain Current For Various Temperatures



**Figure 6.** On-Resistance vs. Temperature For Various Gate Voltage



**Figure 7.** Transfer Characteristic for Various Junction Temperatures

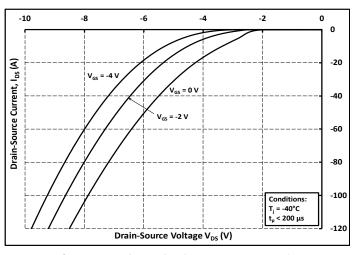


Figure 8. Body Diode Characteristic at -40°C

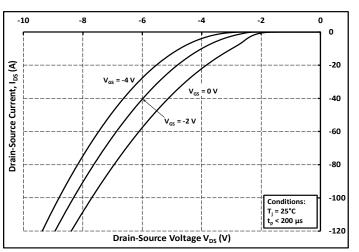
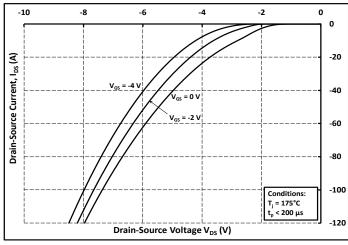


Figure 9. Body Diode Characteristic at 25°C



**Figure 10.** Body Diode Characteristic at 175°C

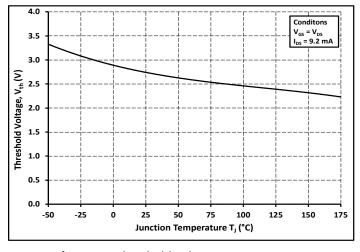


Figure 11. Threshold Voltage vs. Temperature

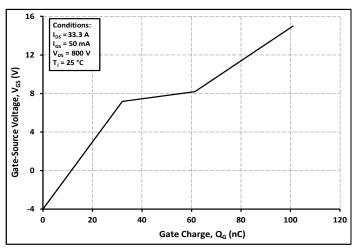


Figure 12. Gate Charge Characteristics

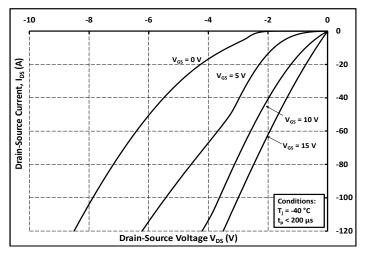


Figure 13. 3rd Quadrant Characteristic at -40°C

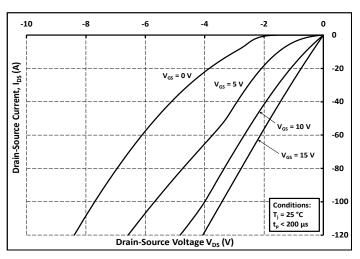


Figure 14. 3rd Quadrant Characteristic at 25°C

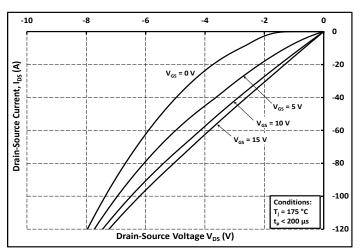


Figure 15. 3rd Quadrant Characteristic at 175°C

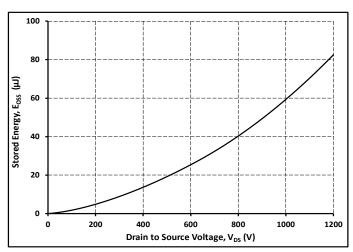
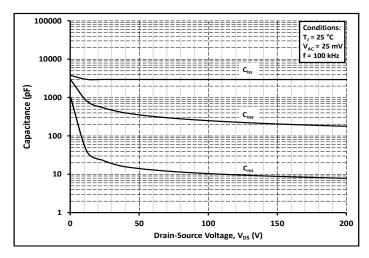
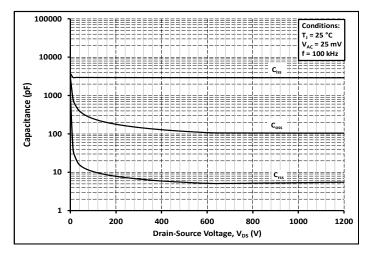


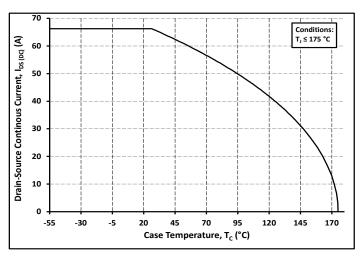
Figure 16. Output Capacitor Stored Energy



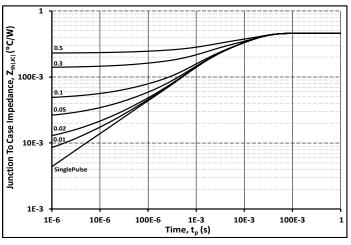
**Figure 17.** Capacitances vs Drain-Source Voltage (0 - 200 V)



**Figure 18.** Capacitances vs Drain-Source Voltage (0 - 1200 V)



**Figure 19.** Continuous Drain Current Derating vs. Case Temperature



**Figure 21.** Transient Thermal Impedance (Junction - Case)

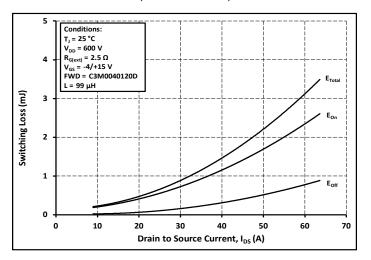
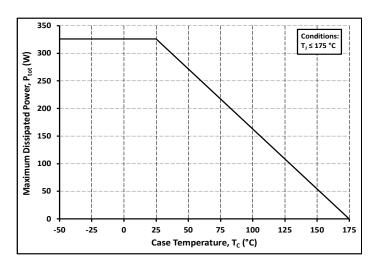


Figure 23. Clamped Inductive Switching Energy vs. Drain Current ( $V_{DD} = 600 \text{ V}$ )



**Figure 20.** Maximum Power Dissipation Derating vs. Case Temperature

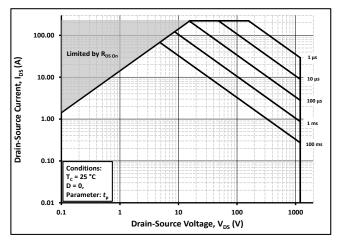
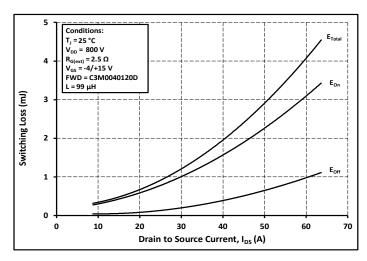


Figure 22. Safe Operating Area



**Figure 24.** Clamped Inductive Switching Energy vs. Drain Current  $(V_{DD} = 800 \text{ V})$ 

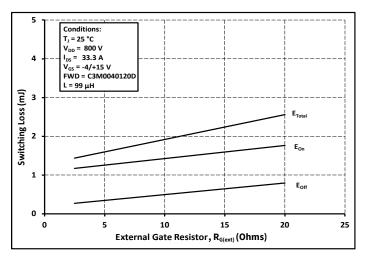


Figure 25. Clamped Inductive Switching Energy vs. R<sub>G(ext)</sub>

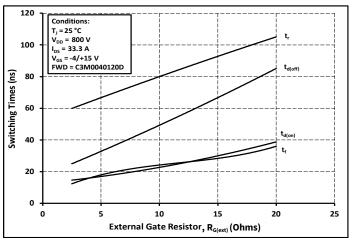


Figure 27. Switching Times vs. R<sub>G(ext)</sub>

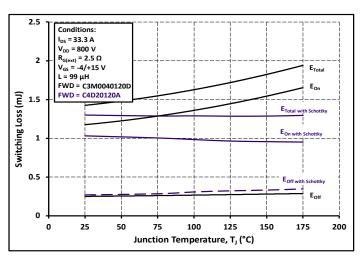


Figure 26. Clamped Inductive Switching Energy vs. Temperature

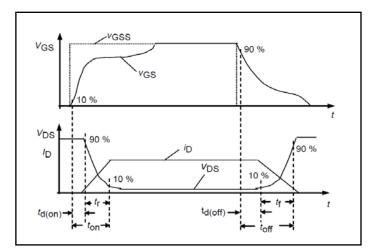


Figure 28. Switching Times Definition

#### **Test Circuit Schematic**

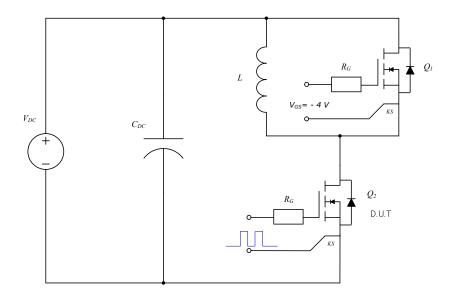
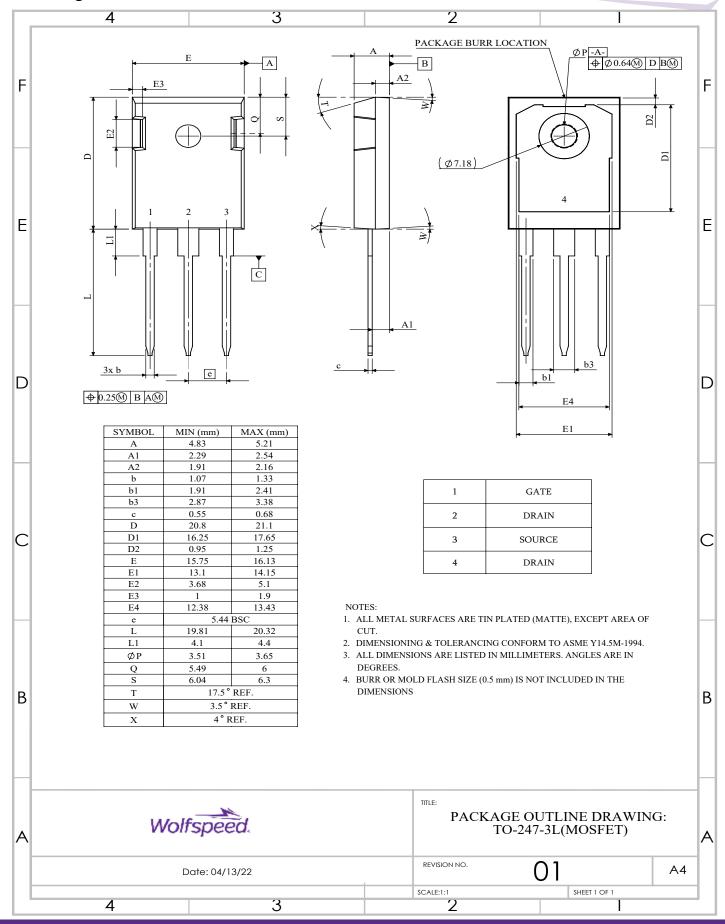


Figure 29. Clamped Inductive Switching Waveform Test Circuit

#### Note:

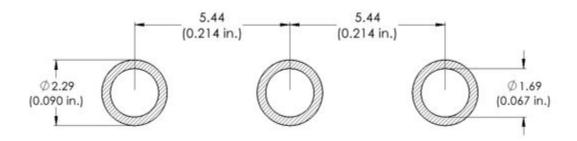
Turn-off and Turn-on switching energy and timing values measured using SiC MOSFET Body Diode as shown above.

## Package Dimensions - TO-247-4L



# Recommended Solder Pad Layout

Primary dimensions in mm



## **Revision History**

Current Revision	Date of Release	Description of Changes
1	October-2020	N/A
2	December-2023	Updated Wolfspeed branding, package drawing, package image, and solder pad layout, added Revision History Table, Table 1 layout revised

#### **Related Links**

- SPICE Models: http://wolfspeed.com/power/tools-and-support
- <u>SiC MOSFET Isolated Gate Driver Reference Design</u>: http://wolfspeed.com/power/tools-and-support
- <u>SiC MOSFET Evaluation Board</u>: http://wolfspeed.com/power/tools-and-support

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The Silicon Carbide MOSFET module switches at speeds beyond what is customarily associated with IGBT-based modules. Therefore, special precautions are required to realize optimal performance. The interconnection between the gate driver and module housing needs to be as short as possible. This will afford optimal switching time and avoid the potential for device oscillation. Also, great care is required to insure minimum inductance between the module and DC link capacitors to avoid excessive VDS overshoot.

#### **RoHS Compliance**

The levels of RoHS restricted materials in this product are below the maximum concentration values (also referred to as the threshold limits) permitted for such substances, or are used in an exempted application, in accordance with EU Directive 2011/65/EC (RoHS2), as implemented January 2, 2013. RoHS Declarations for this product can be obtained from your Wolfspeed representative or from the Product Documentation sections of www.wolfspeed.com.

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REACh substances of high concern (SVHCs) information is available for this product. Since the European Chemical Agency (ECHA) has published notice of their intent to frequently revise the SVHC listing for the foreseeable future, please contact your Wolfspeed representative to ensure you get the most up-to-date REACh SVHC Declaration. REACh banned substance information (REACh Article 67) is also available upon request.

#### **Contact info:**

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